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Japan's comments on WD10373-1
- Test method

1. Static electricity.

Keep 2kV for ESD test of ICC with contacts.

IC Cards with the chip which are corresponding to 2kV have been produced continuing now.

It may be improved at next revision.

2. 3 wheel test.

Keep state as informative annex.

It has been tested by real card conveyance type terminal as agreement between manufacturer and customer.